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Dkt. 04202

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

PCT

OLIVIER MARTY et al.

Serial No. 10/512,077 ✓

Filed: November 5, 2004

For: PROCESS FOR MODIFYING THE PROPERTIES OF A THIN
LAYER AND SUBSTRATE APPLYING SAID PROCESS

INFORMATION DISCLOSURE STATEMENT

Honorable Commissioner for Patents
P.O. Box 1450
Alexandria, Virginia 22313-1450

Sir:

Applicants submit herewith the International Search
Report of the corresponding PCT application, together with a
Form PTO-1449 and copies of the references cited therein.

Respectfully submitted,



Ira J. Schultz
Registration No. 28666



Form PTO-1449

ATTY DOCKET NO.
04202APPLICATION
NO. 10/512,077**INFORMATION DISCLOSURE CITATION
IN AN APPLICATION**

(Use several sheets if necessary)

APPLICANT
Olivier Marty et al.FILING DATE
November 5, 2004

GROUP

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER							DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION	
												YES	NO
	10	2	5	8	2	7	3	3/00	EP Abstract				
	2	6	8	9	9	1	2	10/93	FR w/Abstract				

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

	Romanov et al, "GeSi Films With Reduced Dislocation Density Grown by Molecular-Beam Epitaxy on compliant Substrates Based on Porous Silicon" Applied Physics Letter, etc., Vol. 75, No. 26, Dec. 27, 1999, pp 4118-4120.
	Sanchez et al, "Structural and Morphological Characteristics of InGaAs/GaAs Quantum Well Structures on Tilted (111)BGaAs Grown by MBE", Journal of Crystal Growth etc., Vol. 192, No. 3-4, Sept. 1, 1998, pp 363-371.

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.